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| Notice of References Cited | Application/Control No. 10/543,151 | Applicant(s)/Patent Under Reexamination WATANABE ET AL. | |
| | Examiner Kiet T. Nguyen | Art Unit 2881 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| * | A | US-6,087,659 | 07-2000 | Adler et al. | 250/310 |
| * | B | US-6,465,795 | 10-2002 | Madonado et al. | 250/492.2 |
| * | C | US-6,586,733 | 07-2003 | Veneklasen et al. | 250/306 |
| * | D | US-6,979,822 | 12-2005 | Stewart et al. | 250/310 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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